

FORM PTO-1449 (REV. 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. NIP-261	SERIAL NO.
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT Y. TAKEZAWA et al	
		FILING DATE February 26, 2002	GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
	AA					11002 U.S. PTO
	AB					10/082282
	AC					02/26/02
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					

FOREIGN PATENT DOCUMENTS

	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES <input type="checkbox"/> NO <input checked="" type="checkbox"/>
A.A.	AL 11-330185	11/30/99	Japan (w/ English Abstract)	H01L	21/61	<input type="checkbox"/> <input checked="" type="checkbox"/>
	AM 2000-131243	05/12/00	Japan (w/ English Abstract)	G01N	21/89	<input type="checkbox"/> <input checked="" type="checkbox"/>
	AN 11-235097	08/27/99	Japan (w/ English Abstract)	H02P	9/00	<input type="checkbox"/> <input checked="" type="checkbox"/>
	AO 9-222393	08/26/97	Japan (w/ English Abstract)	G01N	21/27	<input type="checkbox"/> <input checked="" type="checkbox"/>
↓	AP 10-115601	05/06/98	Japan (w/ English Abstract)	G01N	29/00	<input type="checkbox"/> <input checked="" type="checkbox"/>

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	AR	T. Ikeda et al, "Development of the Ultrasonic Degradation Tester for Low Voltage Cables", TRANSACTIONS OF THE INSTITUTE OF ELECTRICAL ENGINEERS OF JAPAN, Vol. 120-B, No. 11, pp. 1437-1442, 2000.
	AS	
	AT	

EXAMINER DATE CONSIDERED

Amir

ALAVI

12-1-2004

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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FOREIGN PATENT DOCUMENTS

SEARCHED	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	AL 11-118773	04/30/99	Japan (w/ English Abstract)	G-01N	29/10	<input type="checkbox"/>	<input checked="" type="checkbox"/>
	AM 10-19856	01/23/98	Japan (w/ English Abstract)	G-01N	29/18	<input type="checkbox"/>	<input checked="" type="checkbox"/>
	AN 7-35732	02/07/95	Japan (w/ English Abstract)	G-01N	29/18	<input type="checkbox"/>	<input checked="" type="checkbox"/>
✓	AO 7-245869	09/19/95	Japan (w/ English Abstract)	H-02H	5/10	<input type="checkbox"/>	<input checked="" type="checkbox"/>
	AP					<input type="checkbox"/>	<input type="checkbox"/>

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

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